

Radio-frequency network analysis

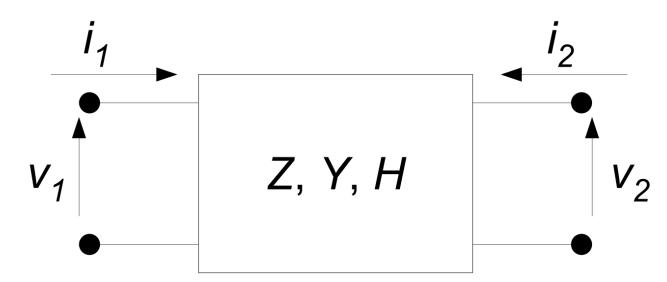
Lecture #15
Electronic measurements
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• Two-port linear devices \rightarrow Linear equations expressing the link among voltages and currents

$$v_1 = z_{11}i_1 + z_{12}i_2$$
 $i_1 = y_{11}v_1 + y_{12}v_2$
 $v_2 = z_{21}i_1 + z_{22}i_2$ $i_1 = y_{21}v_1 + y_{22}v_2$

Impedances

Admittances



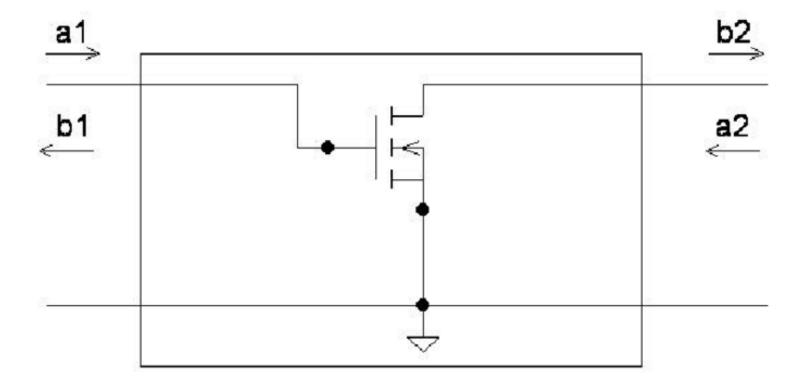
• **Transistors** → Linearized equations → hybrid parameters

$$v_1 = h_{11}i_1 + h_{12}v_2$$

$$i_2 = h_{21}i_1 + h_{22}v_2$$

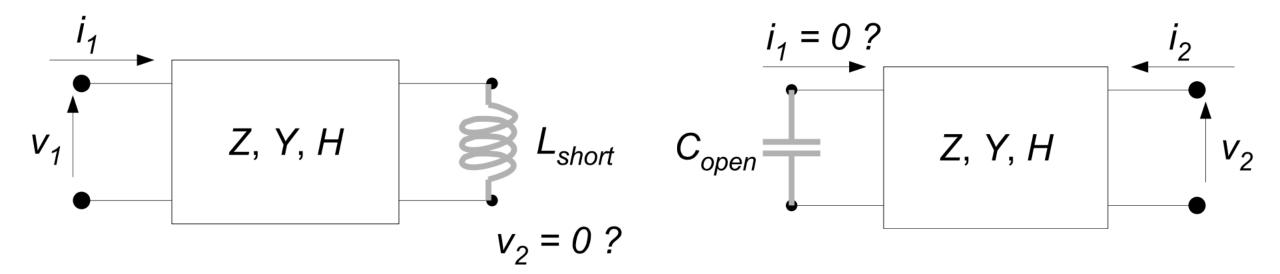
- h_{11} impedance
- h_{22} admittance
- h_{12} and h_{21} dimensionless parameters
- h_{11} determined measuring voltage v_1 and current i_1 at port 1 when port 2 is short-circuited ($v_2=0$)
- h_{22} determined measuring voltage v_2 and current i_2 at port 2 when port 1 is an open circuit ($i_1 = 0$)

Two port model of a transistor



Real conditions:

- a small inductance L_{short} is introduced between terminals when port 2 is short-circuited
- a small capacitance C_{open} is found between terminals when port 1 is left open



- High frequencies:
 - Adverse effects on accuracy due to these parameters
 - Signal reflections at the terminations
- **High-frequency electronic circuits**: impedance-matched systems \rightarrow ideally, signals propagate unaltered from one functional block to the next without reflection
- A two-port device might be characterized by just one parameter
 - Attenuation (passive device)
 - Amplification (active device)
- Reflections \rightarrow Reflection coefficient Γ

- Measurements on high-frequency devices under test operating in impedance matching conditions:
 - Test conditions are less difficult to be set
 - Measurements are referred to test conditions that are closer to the normal operation of the device
- Measurements need to be referred to a different set of parameters:
 - Incident wave V_i
 - Reflected wave V_r

V complex number → phasor of a sinusoidal waveform

$$v(t) = \sqrt{2} \cdot |\mathbf{V}| \cos(2\pi f t + \angle \mathbf{V}) = \mathbb{R} \left[\sqrt{2} \cdot |\mathbf{V}| \cdot e^{j2\pi f t} \right]$$

- f generic frequency value
- |V| sinewave root mean-square value
- Z_0 characteristic impedance

Incident power
$$\frac{|V_i|^2}{Z_0}$$

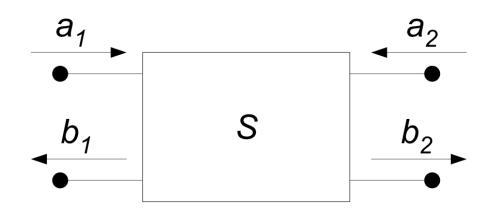
Reflected power
$$\frac{|V_r|^2}{Z_0}$$

• Normalized values referred to V_i and V_r :

$$a = \frac{\mathbf{V}_i}{\sqrt{Z_0}}$$
$$b = \frac{\mathbf{V}_r}{\sqrt{Z_0}}$$

Two port equations:

$$b_1 = s_{11}a_1 + s_{12}a_2$$
$$b_2 = s_{21}a_1 + s_{22}a_2$$



- s_{11} , s_{12} , s_{21} , s_{22} scattering parameters (s-parameters)
- $|a|^2$ and $|b|^2$ incident and reflected power

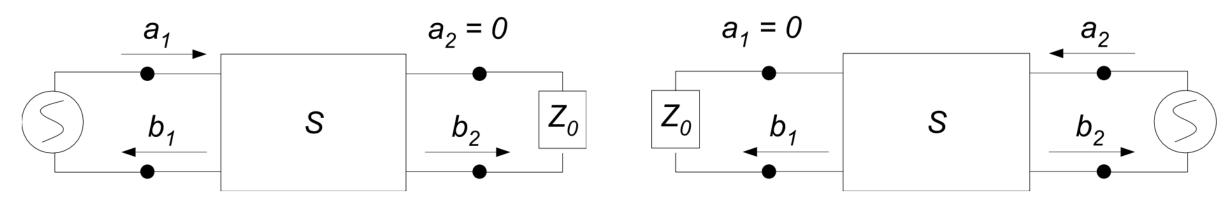
$$s_{11} = \frac{b_1}{a_1}\Big|_{a_2=0}$$
 from which $s_{11} = \frac{\mathbf{V}_{r_1}}{\mathbf{V}_{i_1}}\Big|_{\mathbf{V}_{i_2}=0} = \Gamma_1$

Complex reflection coefficient

$$s_{21} = \frac{b_2}{a_1}\Big|_{a_2=0}$$
 from which $s_{21} = \frac{\mathbf{V}_{r_2}}{\mathbf{V}_{i_1}}\Big|_{\mathbf{V}_{i_2}=0}$

Complex **transmission** coefficient

- Determination of s_{11} and s_{21} :
 - A matched generator providing the incident wave V_{i1} at port 1
 - A **load impedance** Z_0 on the opposite port 2, to ensure that wave b_2 , "outgoing" from port 2, is not reflected back
 - Two measuring units for waves V_{r1} and V_{r2} on both ports



- (a) measurement configuration, port 1
- (b) measurement configuration, port 2



- Crucial requirements:
 - Values of s-parameters are **complex numbers** that are determined as ratios of two vectors. This requires the capability to measure both **a magnitude** ratio and a phase difference (between reflected and incident wave)
 - At any point along a transmission line measured voltage is the (vector) superposition of V_i and V_r . The two components can only be separated on the basis of their **propagation direction**
 - Frequencies for s-parameter measurement may range from a few MHz to several tens of GHz



Network analyzers

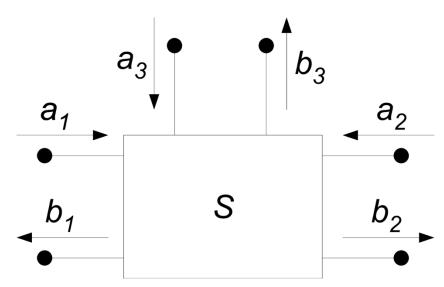
Directional coupler

- Separates the incident and reflected waves
- Three-port s-parameter model

$$b_1 = s_{11}a_1 + s_{12}a_2 + s_{13}a_3$$

$$b_2 = s_{21}a_1 + s_{22}a_2 + s_{23}a_3$$

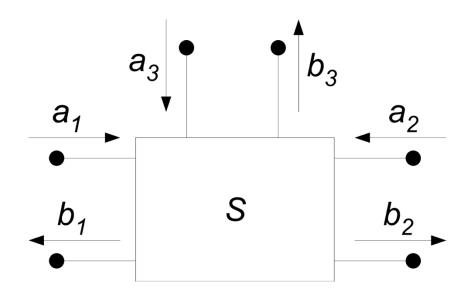
$$b_3 = s_{31}a_1 + s_{32}a_2 + s_{33}a_3$$



- The directional coupler is placed between the matched generator providing the test sinewave and one port of the device under test
- **Termination impedance** for port 3 is $Z_0 \rightarrow \text{No reflection}$, $a_3 = 0$

Directional coupler

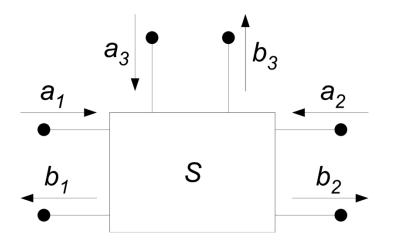
- Parameters of a directional coupler:
 - Coupling factor, defined by the power ratio: $\frac{|b_3|^2}{|a_2|^2}$ with $a_1 = 0$, $a_3 = 0 \rightarrow |s_{32}|^2$
 - Reverse coupling factor, or isolation, defined by the power ratio: $\frac{|b_3|^2}{|a_1|^2}$ with $a_2=0,\,a_3=0 \rightarrow |s_{31}|^2$
 - Insertion loss, defined by the power ratio: $\frac{|b_2|^2}{|a_1|^2}$ with $a_2=0$, $a_3=0 \rightarrow |s_{21}|^2$



Directional coupler

- Passive device $\rightarrow |s_{32}| \le 1$ for all s-parameters
- All parameters are expressed in dB
- "Minus" sign is usually omitted → implied in terms like "loss" or "attenuation"

• **Directivity:** capability to separate the incident wave from the reflected wave and present at port 3 an output proportional only to the latter



Directivity

- Assume that total reflection occurs at port 2, so that $a_2 = b_2$
- Coupler output at port 3:

$$b_3 = s_{31}a_1 + s_{32}b_2 = s_{31}a_1 + s_{32}s_{21}a_1$$

- $s_{32}s_{21}a_1$ coupling with port 2
- $s_{31}a_1$ "undesired" direct coupling of port 1 to port 3
- Power measured at port 3:

$$P_3 = (|s_{32}| \cdot |s_{21}| \cdot |a_1|)^2 + (|s_{31}| \cdot |a_1|)^2 = |s_{32}|^2 \cdot |b_2| \left| 1 + \frac{|s_{31}|^2}{|s_{32}|^2 \cdot |s_{21}|^2} \right|$$

Directivity

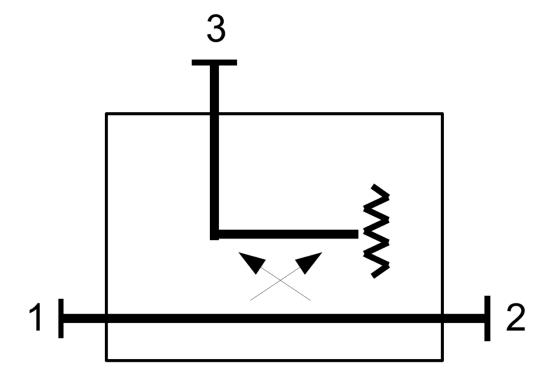
$$P_3 = (|s_{32}| \cdot |s_{21}| \cdot |a_1|)^2 + (|s_{31}| \cdot |a_1|)^2 = |s_{32}|^2 \cdot |b_2|^2 \left| 1 + \frac{|s_{31}|^2}{|s_{32}|^2 \cdot |s_{21}|^2} \right|$$

- Proportional to the power $|b_2|^2$ reflected into port 2, times the coupling factor s_{32}
- The term in square brackets in should be as close to 1 as possible
- Directivity: indication of the influence of power from the generator on the measurement of reflected waves
- Ratio of the isolation factor to the product between coupling factor and insertion loss

$$\begin{aligned} \operatorname{Directivity}_{[dB]} &= -20 \log_{10} \frac{|s_{31}|^2}{|s_{32}|^2 \cdot |s_{21}|^2} = \\ &= \operatorname{Isolation}_{[dB]} - \operatorname{Coupling}_{[dB]} - \operatorname{Insertion loss}_{[dB]} \end{aligned}$$

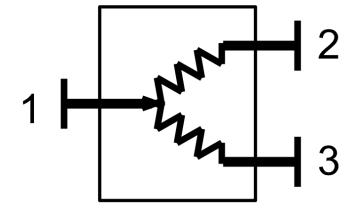
Directivity

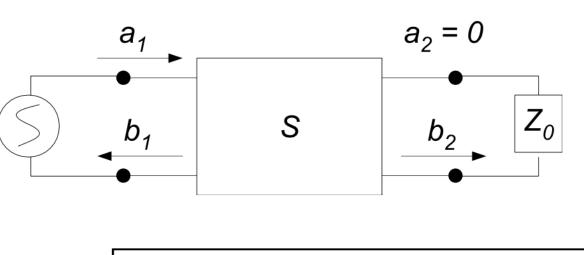
- Directivity is defined as a **power ratio** \rightarrow no phase characteristic
- Complete characterization of the measuring system input-output behaviour (magnitude and phase) \rightarrow preliminary calibration phase

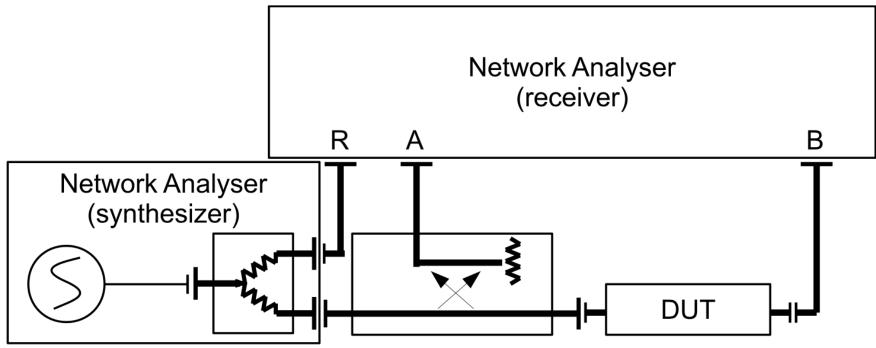


Power splitter

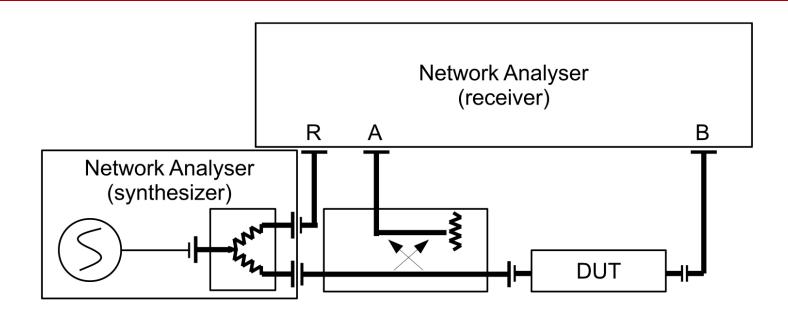
- Passive circuit which divides the power input into equal parts at the two outputs, while ensuring impedance matching
- Fully characterized by a set of three equations with 9 s-parameters
- Ideal operation: half of the input power is found at each of the two output ports, corresponding to a 3 dB attenuation





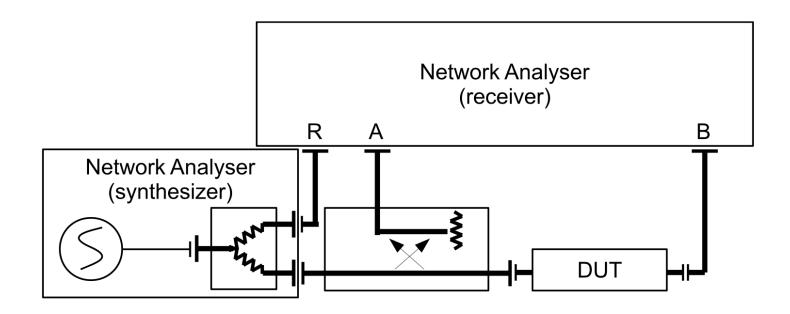






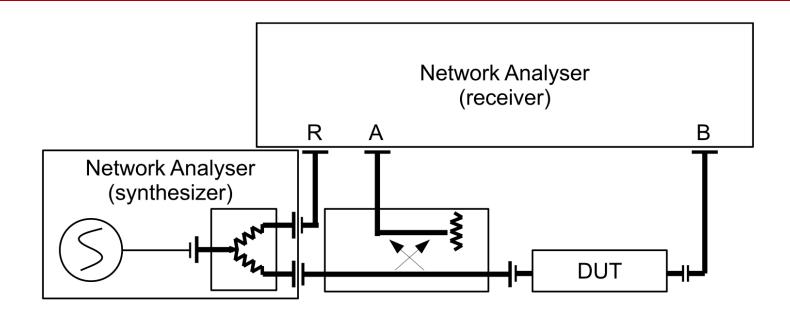
- A, B and R measurement inputs
- Through the power splitter, the signal from the radio-frequency generator is sent both to R and to the DUT
- Responses from the DUT are measured, respectively, at input B for transmission and at input A for reflection



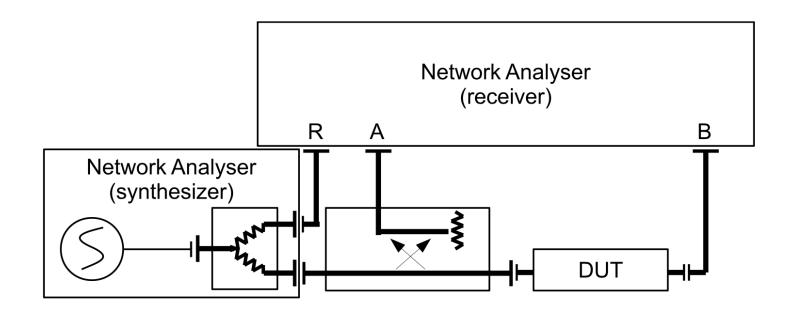


- Signal power at the DUT input is lower than power measured at input R
 because of the insertion loss of the directional coupler
- Power measured at input A is proportional to power reflected by the DUT.
 The coupling factor of the directional coupler also has to be considered





 Synthesizer: generates a variable frequency sinewave with controlled, stable amplitude, that provides the input stimulus to the device under test. Frequency may vary between a minimum value of about 100 kHz and a maximum value that may reach up to around a hundred GHz



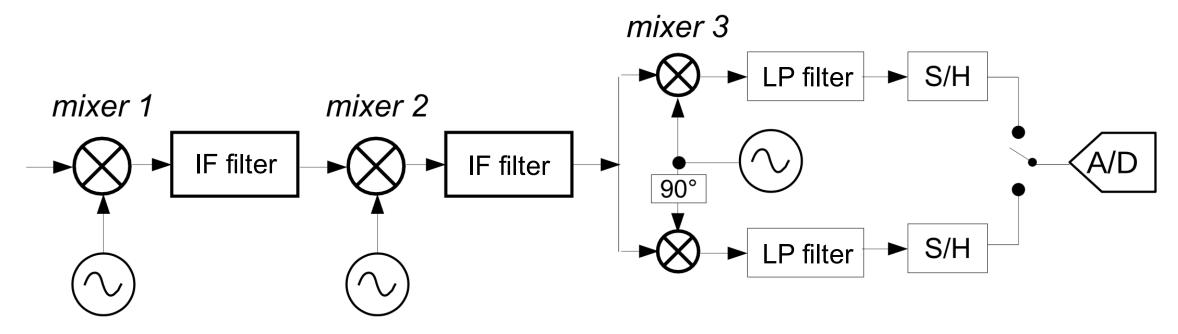
• **Receiver**: measures sinewave magnitudes and phases at each of the three input channels. Indicating by V_R , V_A and V_B the resulting three phasors, measurements of the complex transmission coefficient s_{21} and of the complex reflection coefficient s_{11} are given by the two ratios:

$$\hat{s}_{21} = \frac{\mathbf{V}_B}{\mathbf{V}_R} \qquad \qquad \hat{s}_{11} = \frac{\mathbf{V}_A}{\mathbf{V}_R}$$

- Accurate phase measurement → No distortion
- DUT (e.g. radio-frequency amplifier) **may add distortion** even when designed to operate as a linear device
- Non-linearities should be avoided \rightarrow the aim of network analyzer measurements is the determination of parameters in a linear model

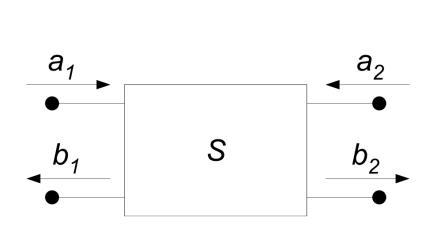
 The response of analyzed devices may depend quite significantly on frequency → large amplitude dynamics (at least 100 dB)

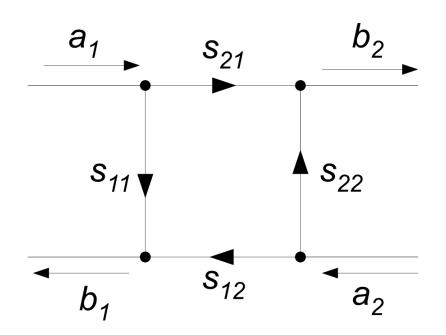
Network analyzer Receiver



- Swept-frequency spectrum analyzer → Superheterodyne
- Three **cascaded mixer stages** \rightarrow high frequency selectivity and wide amplitude dynamics
- The outputs of the final mixer stage are then sampled and digitized
- Input frequency is known \rightarrow synthesizer and receiver frequencies are tuned

- System calibration \rightarrow ensure the accuracy of measurement results
- Radio-frequency measurements \rightarrow At high frequencies the influence of minor elements such as cables and connectors may become significant
- In network analyzers system calibration is essential to guarantee the validity of results

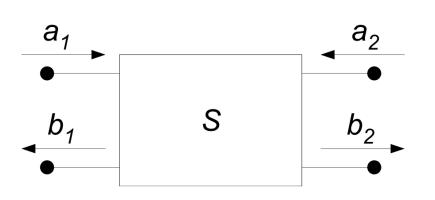


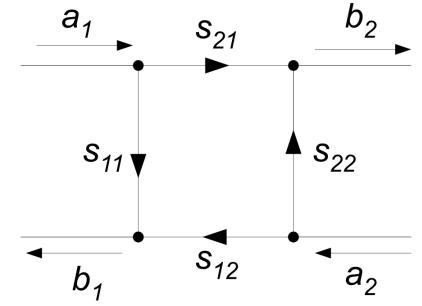




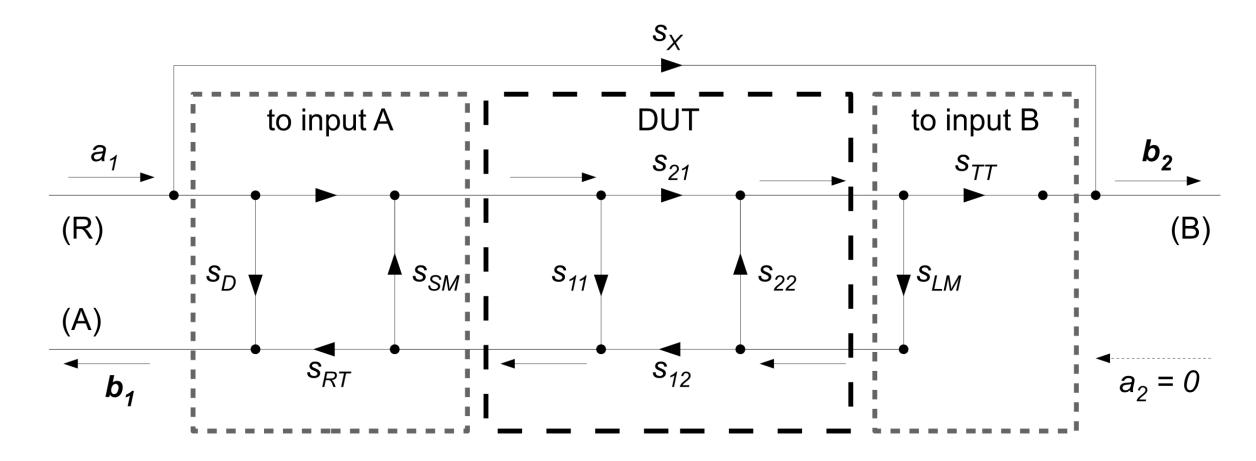
- Quantities a and b propagate along arcs, whose orientation is shown by arrows
- Nodes are summing points, with arcs converging towards a node or spreading out from it, according to orientation
- Parameter s_{ij} denotes that if a_j is the quantity entering an arc, its output will

be $s_{ij}a_j$

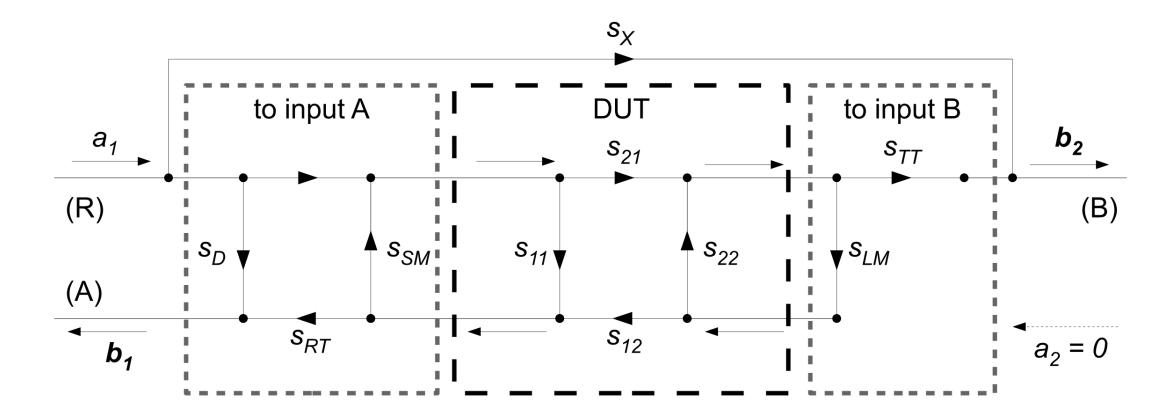




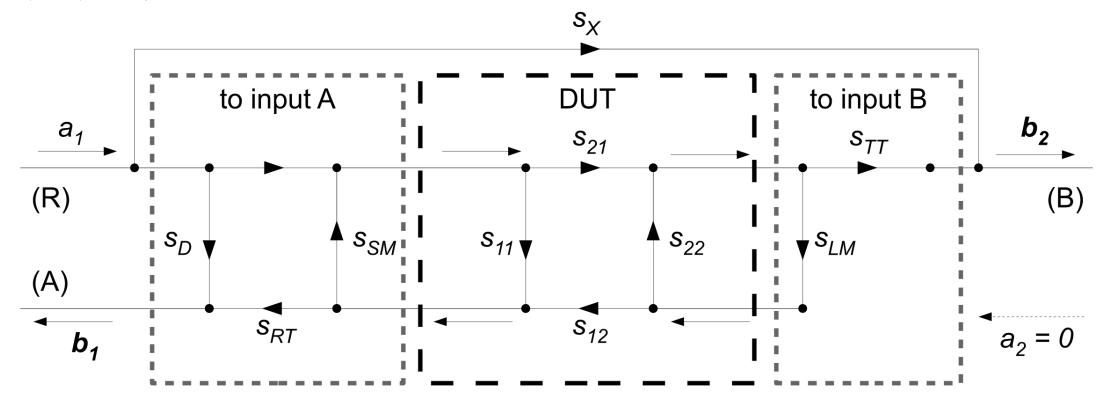
- Factors affecting the measurement result
- Effects of test set-up non-ideality



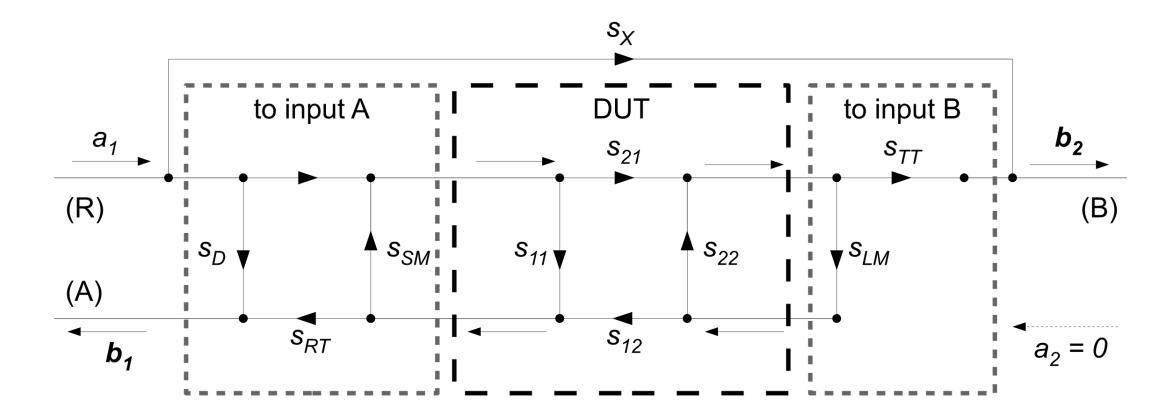
• s_D : limitations in the **directivity of the directional coupler**, that affect input A of the network analyzer. It is a complex parameter, which allows to also consider the effects on the measurement of phase



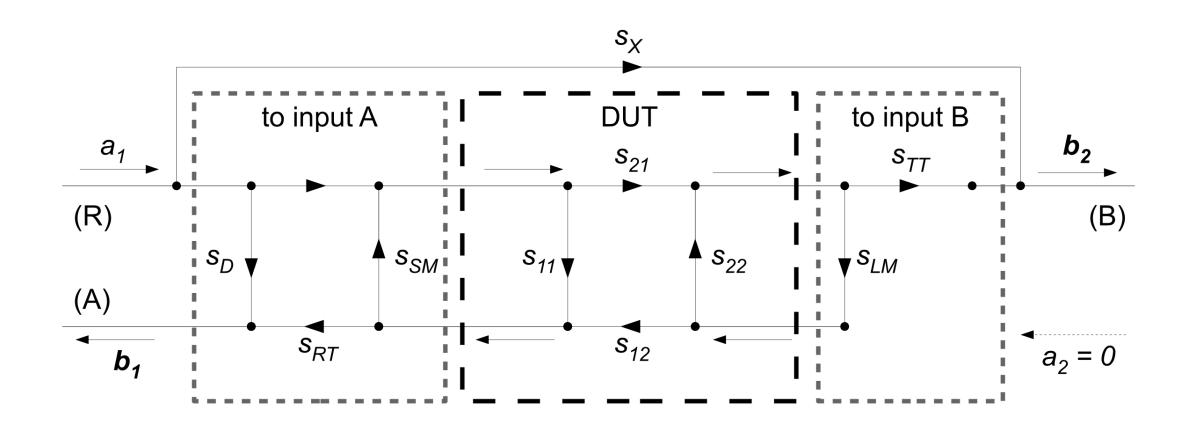
• s_{SM} and s_{LM} : possible effects of impedance mismatch between the measuring system and DUT ports (impedances not corresponding to Z_0 . On the synthesizer side this is called **source mismatch**. Similarly, **load mismatch** (LM) may occur on the side of the termination load



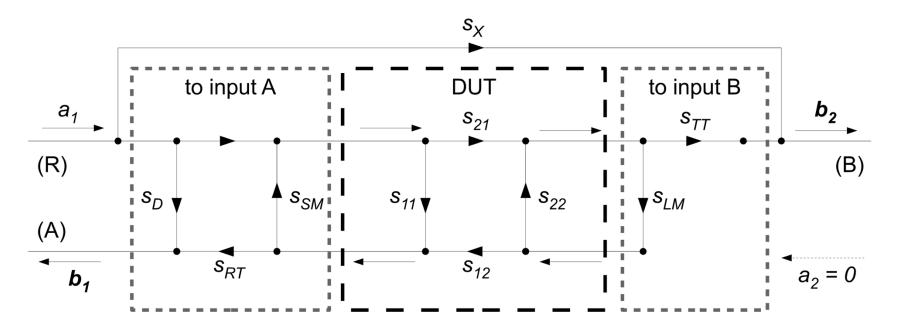
• s_{RT} and s_{TT} : **tracking errors** caused by differences between the frequency responses of input channels A and R (in this case, **reflection tracking**), or of channels B and R (**transmission tracking**)



• s_X : crosstalk effects caused by undesired coupling between the DUT ports



- 6 parameters (dependent on frequency) \rightarrow calibration the test set-up in the configuration where the input stimulus is sent to DUT port 1
- 6 parameters for port 2
- 12 complex parameters at each frequency

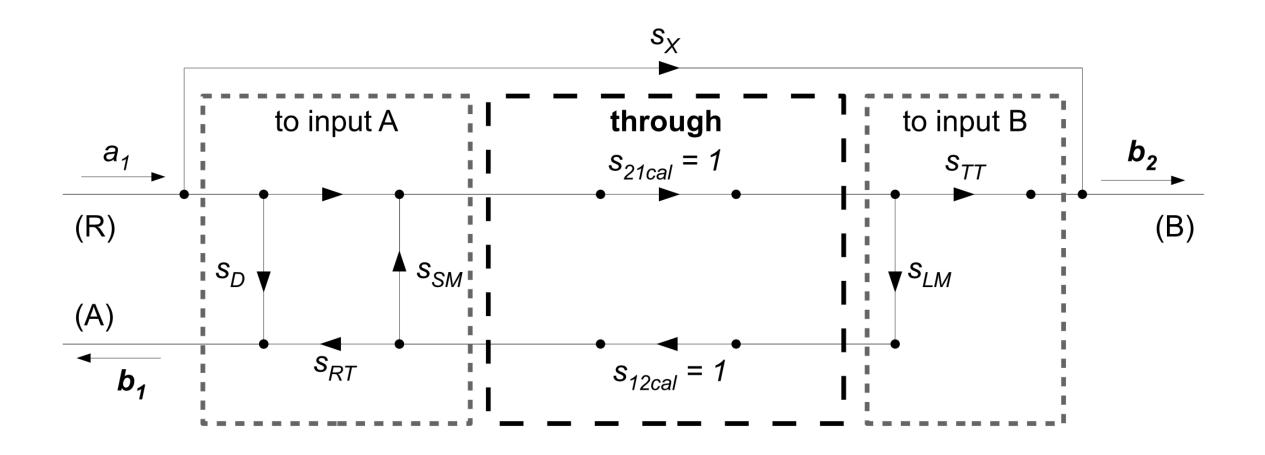




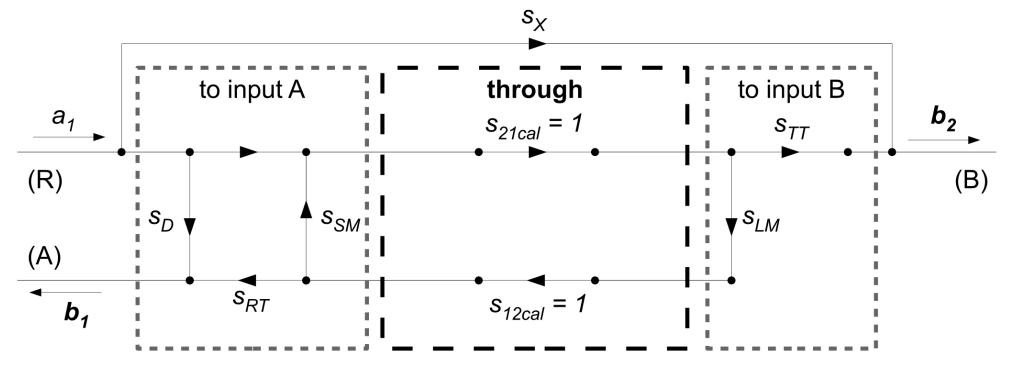
- Commonly used calibration method → set of reference conditions by means of four circuit elements:
 - Short circuit (S)
 - Open circuit (O)

- SOLT
- Load impedance of known value, usually Z_0 (load, L)
- Matched line (through, T)
- Calibration: set of equations correlating measurements to calibration parameters only

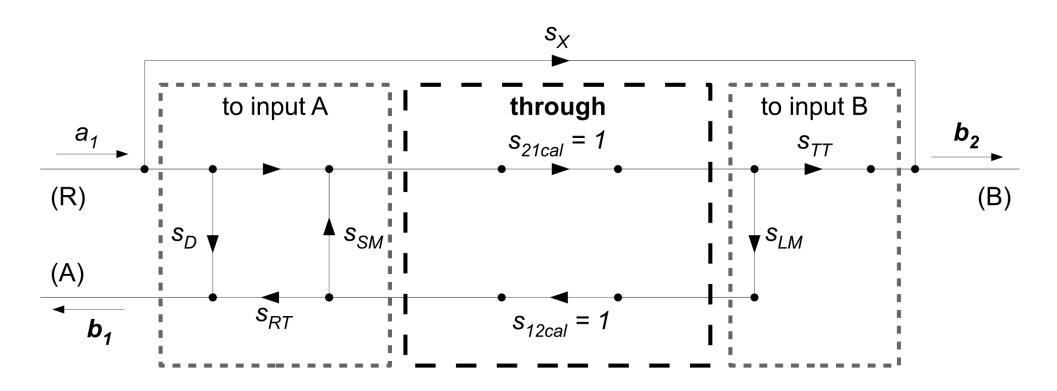
Example: use of a length of matched line (through) as the calibration reference

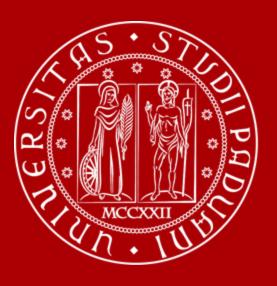


- **s**-parameters: $s_{12cal} = s_{21cal} = 1$, $s_{11cal} = s_{22cal} = 0$
- By measuring ratios $\frac{\mathbf{V}_A}{\mathbf{V}_R}$ and $\frac{\mathbf{V}_B}{\mathbf{V}_R}$, that are primarily affected by tracking and mismatch errors (parameters s_{RT} , s_{TT} , s_{SM} and s_{LM}), the actual frequency response of the measuring system alone is determined



- Ideal through: frequency response having unit magnitude and linear phase characteristic proportional to the line length
- Correction factors based on the measured response can be calculated and stored as calibration data





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